

<b>Notice of References Cited</b>	Application/Control No. 09/973,270	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Linda Wong	Art Unit 2634	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Juodawlkis et al, "Optically Sampled Analog-to-Digital Converters", IEEE Transactions on Microwave Theory and Techniques, Vol. 49, No. 10, October 2001
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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